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(71) Applicant: **ILLUMINA, INC.** [US/US]; 5200 Illumina Way, San Diego, California 92122 (US).

(72) Inventors: **BAKER, Thomas**; 5200 Illumina Way, San Diego, California 92122 (US). **EARLY, Kevin**; 5200 Illumina Way, San Diego, California 92122 (US). **ZHANG,**

Siqi; 5200 Illumina Way, San Diego, California 92122 (US). **ABASKHARON, Rachel**; 5200 Illumina Way, San Diego, California 92122 (US). **PRABHU, Anmiv**; 5200 Illumina Way, San Diego, California 92122 (US). **WEN, Patrick**; 5200 Illumina Way, San Diego, California 92122 (US).

(74) Agent: **RARIDEN, John M.** et al.; P.O. Box 692289, Houston, Texas 77269 (US).

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(54) Title: SEQUENCER FOCUS QUALITY METRICS AND FOCUS TRACKING FOR PERIODICALLY PATTERNED SURFACES

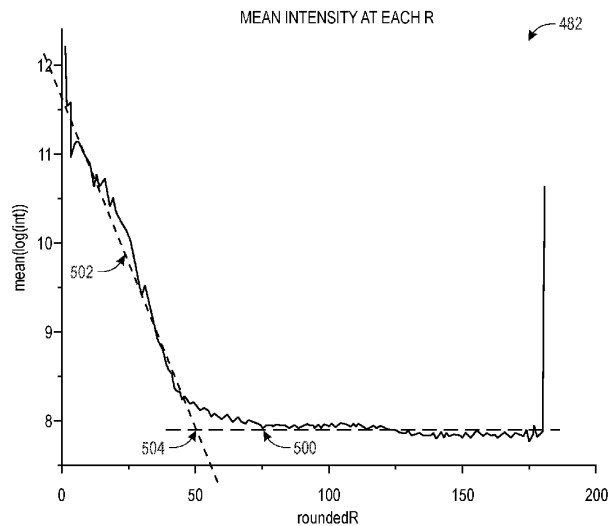


FIG. 11

(57) Abstract: Generation and use of a focus quality metric that is intensity independent is described. In one example, the focus quality metric is generated by acquiring an image, such as an image of a patterned surface of a flow cell, and processing all or part (e.g., a sub-region or sub- image) to generate a Fourier transform of the respective image data. By way of example, in one embodiment a discrete Fourier transform may be applied to a sub-region of an image of a patterned flow cell surface. A focus quality metric that is intensity independent may be derived from the Fourier transform of the image data.

[Continued on next page]

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